

Notice of References Cited

Application/Control No.	Applicant(s)/Pate	nt Under	
09/769,438	Reexamination JOY ET AL.		
Examiner	Art Unit		
Van Kim T. Nguyen	2661	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,725,311	04-2004	Joy et al.	710/305
•	В	US-6,701,371	03-2004	Lee, Hee-jin	709/231
	С	US-6,522,654	02-2003	Small, Donald E.	37.0/400
	D	US-6,496,862	12-2002	Akatsu et al.	709/224
	E	US-6,496,509	12-2002	Fant, Richard	370/400
	F	US-6,434,117	08-2002	Momona, Morihisa	370/236
	G	US-6,430,635	08-2002	Kwon et al.	710/104
	Н	US-6,272,581	08-2001	Leung et al.	710/313
	1	US-6,266,729	07-2001	Leung et al.	710/313
	J	US-6,219,697	04-2001	Lawande et al.	709/221
	K	US-5,991,520	11-1999	Smyers et al.	710/100
	L	US-5,774,695	06-1998	Autrey et al.	703/26
	М	US-2002/0141418	10-2002	BEN-DOR et al.	370/401

FOREIGN PATENT DOCUMENTS

TORLIGH FAILHT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0				•	
	Р					
	Q					
	R					
	S					
	Т				, <u>21 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 - 1 -</u>	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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